

$\sim fs$

# Measurement of ultrashort electron and x-ray beams for x-ray free-electron lasers

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33<sup>rd</sup> International  
**Free Electron Laser Conference**  
22-26 AUGUST 2011 SHANGHAI, CHINA



# Outline

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- Motivation and background;
- Overview of ultrashort diagnostics;
- **Experimental study of longitudinal mapping with a high-resolution spectrometer at LCLS;**
- **An X-band transverse deflector for e-beam and x-ray pulse measurement;**
- Discussions on optical streaking techniques.

# Motivation/background

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- ❑ Growing interests in a few fs or even sub-fs x-ray pulses.
- ❑ LCLS operating at  $\sim 20$  pC or using slotted-foil has delivered x-rays to the users, with estimated duration of a few fs.
- ❑ However, the resolution of the present e-beam diagnostics at LCLS is about 10 fs rms.
- ❑ The characterization on the x-ray pulse duration is also very challenging, even at 100s fs scale.
- ❑ Need techniques with 1-fs resolution, for both e-beams and x-rays.

# Overview: e-beams (I)

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## Existing methods of e-beam longitudinal diagnostics

- S-band/C-band transverse deflector:  
*~10 fs rms resolution at LCLS, time-domain, direct measurement;*  
(LCLS, FLASH, Spring-8, ...)
- Single-shot spectrometer:  
*frequency-domain;* (FLASH, LCLS (under construction), ...)
- Relative bunch length monitor (BLM) from coherent edge radiation or diffraction radiation:  
(LCLS, FLASH, ...)
- Electro-optic (EO) method: (FLASH, ...)

# Overview: e-beams (II)

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New techniques have been proposed/developed\*:

➤ longitudinal-to-transverse mapping:

chicane + deflector (Xiang and Ding, PRSTAB13 094001 (2010))

➤ optical streaking or deflecting

➤ RF + optical deflecting:

two orthogonally oriented deflecting (Andonian et al., PRSTAB14 072802 (2011))

➤ optical replica synthesizer: Saldin et al.

➤ **longitudinal mapping: time → energy** (this talk)

\* Just pick a few examples here.

# Overview: x-ray pulses\*

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## ➤ X-ray auto-correlation

Difficult due to vanishingly small cross-sections in nonlinear processes

Geloni et al., two undulators + fresh bunches

## ➤ x-ray gas interaction + laser or THz fields streaking

*next talk, A. Maier*

## ➤ Statistical analysis

J. Wu et al. FEL10; A. Lutman et al. WEOA2, FEL11.

## ➤ Optical afterburner

N. Stojanovic, WEOA4, FEL11

## ➤ X-band transverse deflector (this talk)

\* Just pick a few examples here.

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## Longitudinal mapping with a high-resolution energy spectrometer\*:

- Review of the method
- Experimental setup and results

*\*Z. Huang et al., PRSTAB 13, 092801 (2010),  
Presented at FEL10.*

*\* Z. Huang et al., PAC11, THP183*

# Apply this method to measure fs bunches

To high-resolution energy spectrometer

Slightly adjust BC2  $R_{56}$   
add a diagnostic chicane  $R'_{56}$

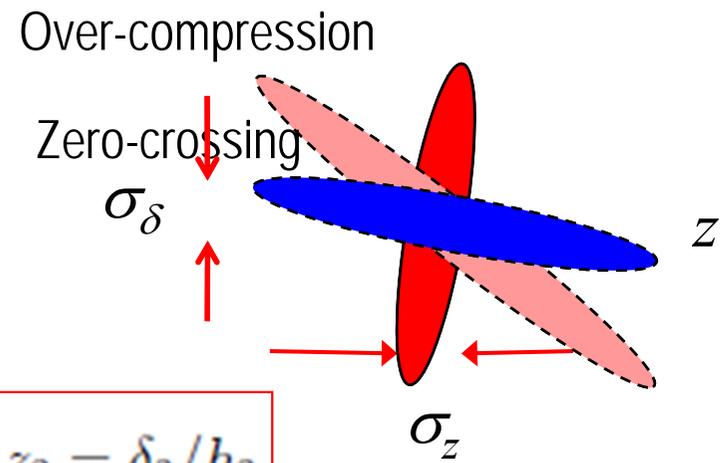


$$\begin{pmatrix} z_3 \\ \delta_3 \end{pmatrix} = \begin{pmatrix} 1 & 0 \\ h_3 & 1 \end{pmatrix} \begin{pmatrix} 1 & R'_{56} \\ 0 & 1 \end{pmatrix} \begin{pmatrix} z_2 \\ \delta_2 \end{pmatrix}$$

$$= \begin{pmatrix} 1 & R'_{56} \\ h_3 & 1 + h_3 R'_{56} \end{pmatrix} \begin{pmatrix} z_2 \\ \delta_2 \end{pmatrix}$$

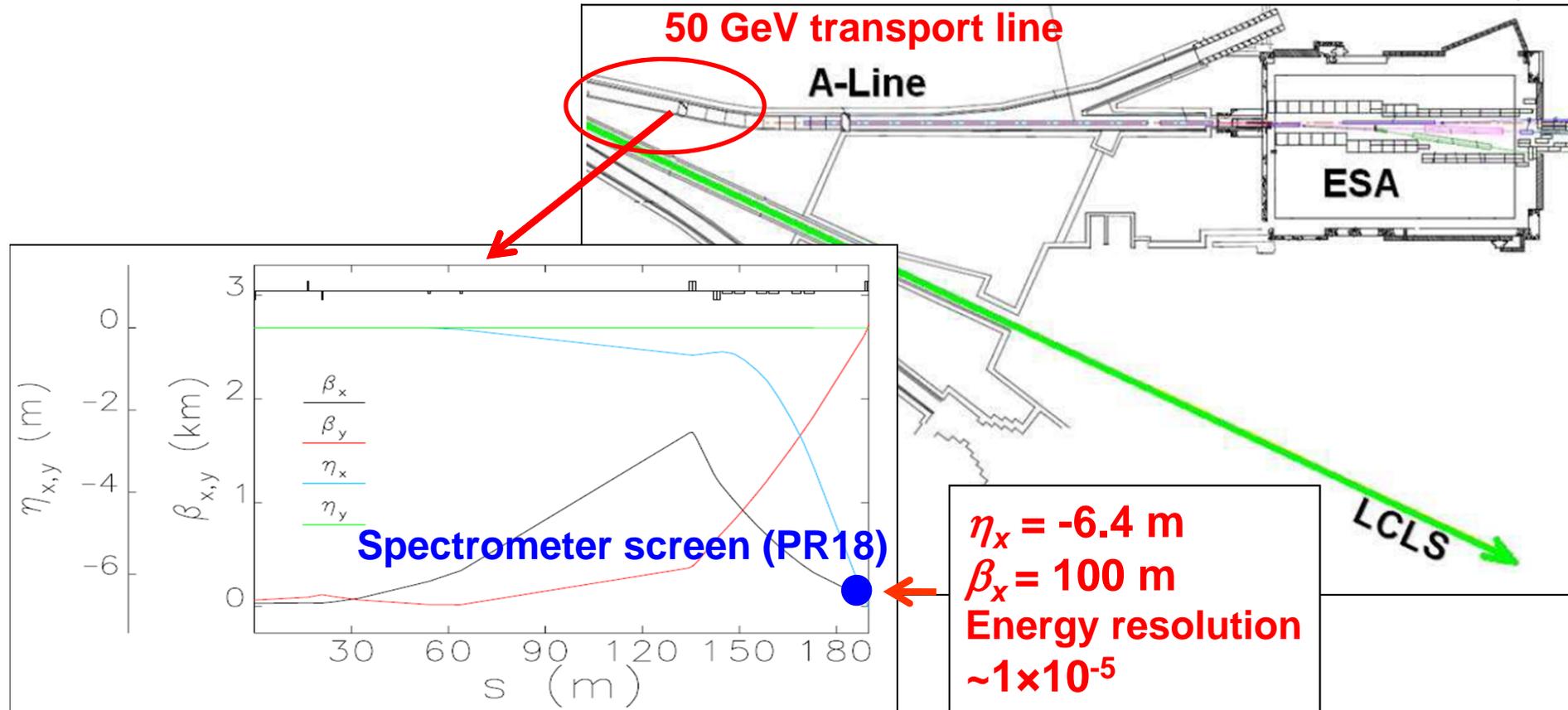
$= 0$

$z_2 = \delta_3 / h_3$



- Diagnostic chicane can be part of BC2
- Final energy spread/profile corresponds to short bunch length/profile
- Wakefield of long linac must be taken into account

# A-line as a high-resolution spectrometer

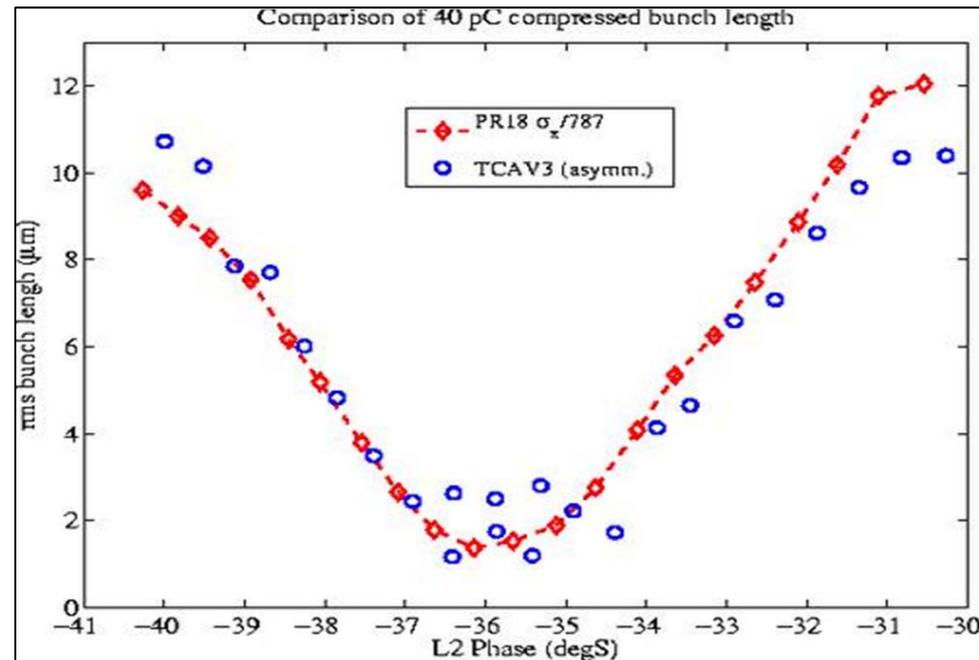


Updated the screen from aluminum to ZnS (Zinc Sulfide),  $\sim 0.1$  mm thickness.  
 Measured resolution of  $250 \mu\text{m}$  in  $\sigma_x$  with the new screen.

# Calibration and Benchmark

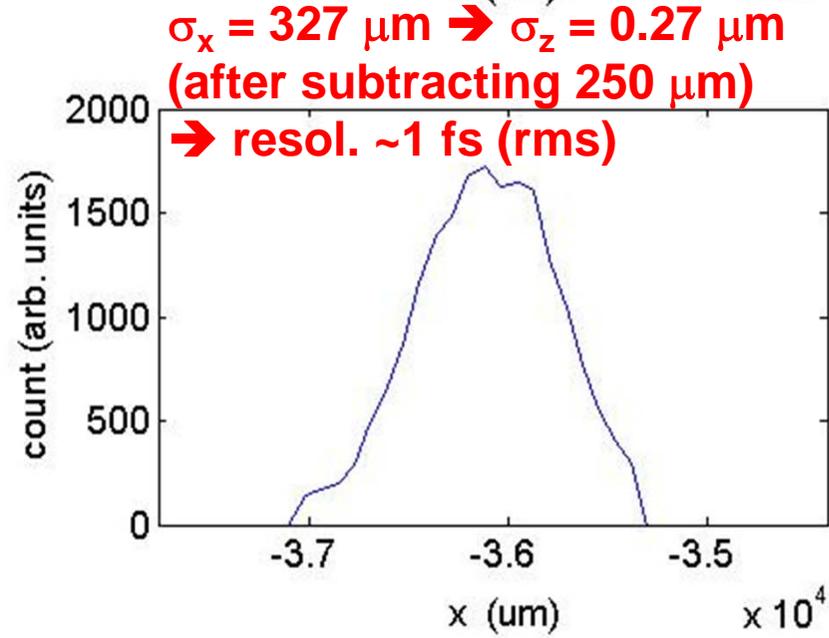
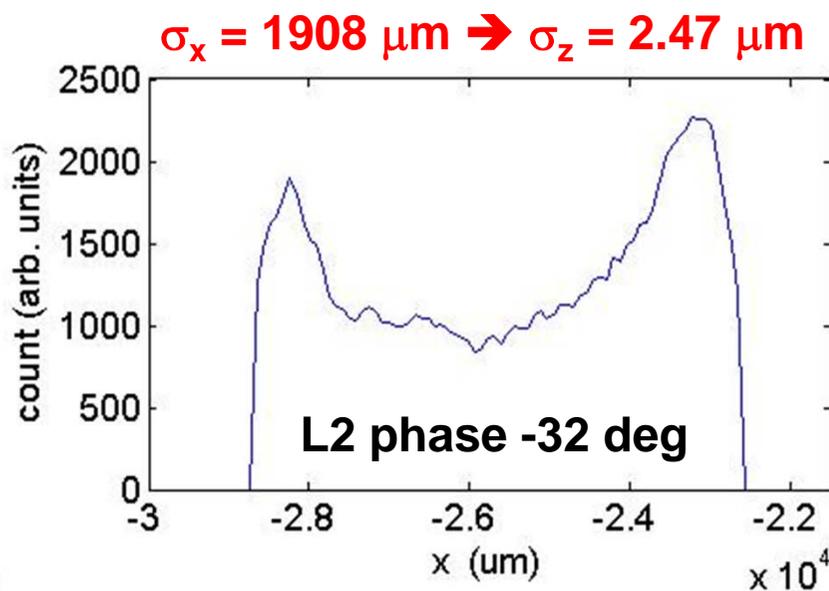
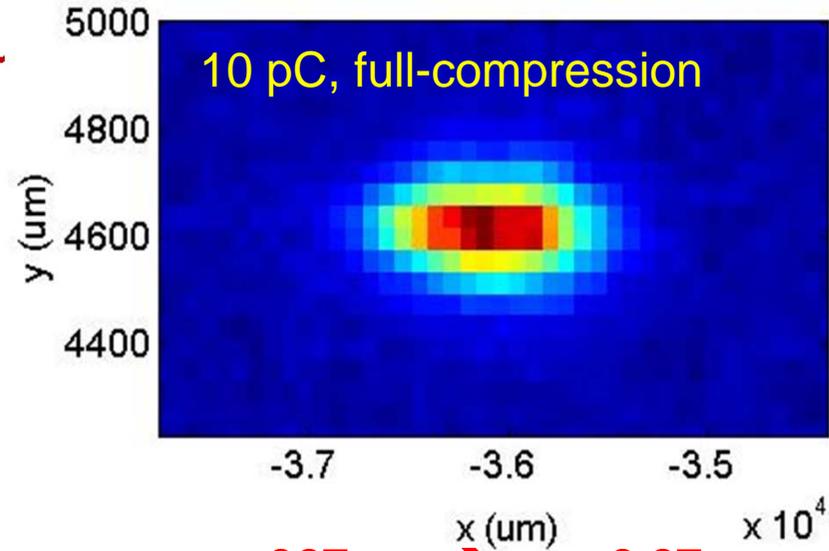
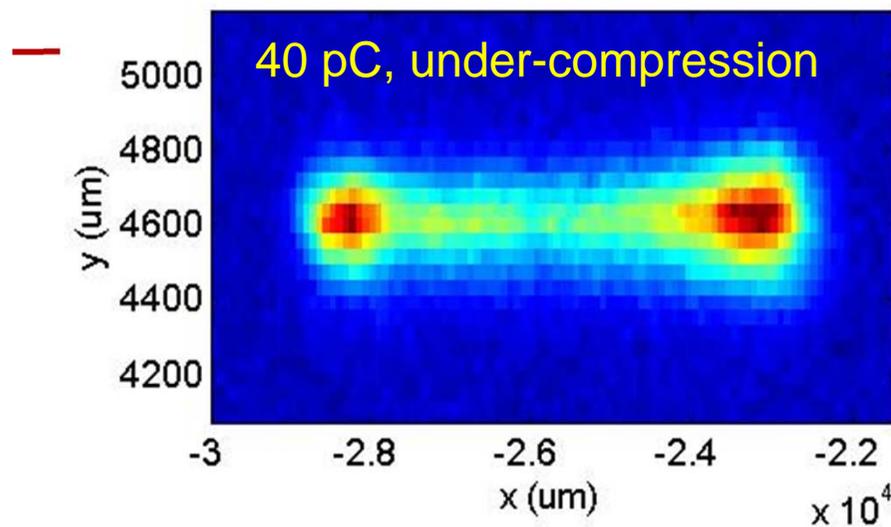
- Calibration factor:  $\rightarrow \sim 770\text{-}840 \mu\text{m}/\mu\text{m}$  bunch length
  - ❖ Measure PR18 horizontal central position vs L3 phase;
  - ❖ OR, use measured dispersion and chirp.
- TCAV3 runs out of resolutions at about  $\sim 3 \mu\text{m}$  (10 fs) bunch length level

40 pC measured data\*



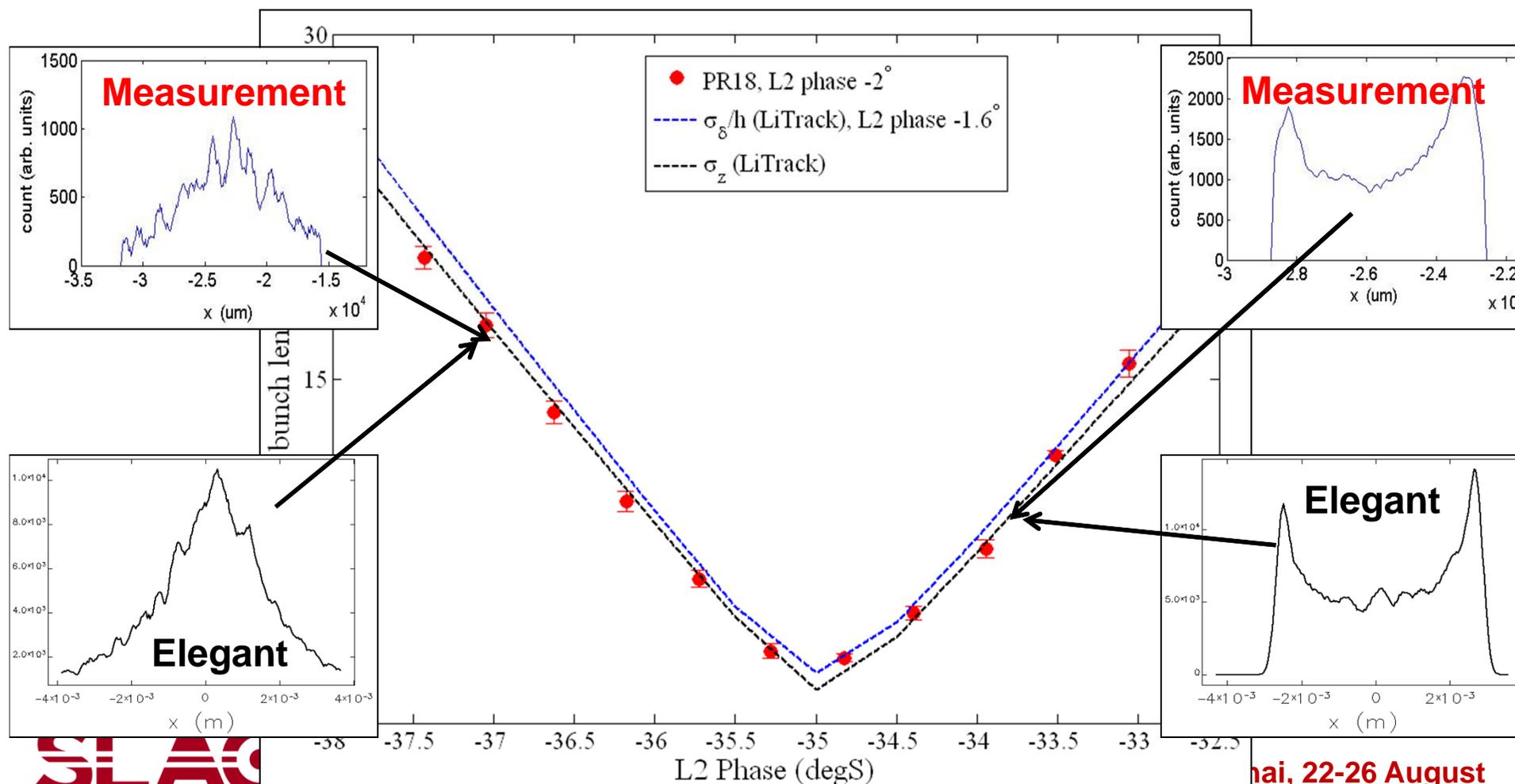
\* With an old aluminum screen.

# Measurement examples on PR18 (new screen)



# Measurement vs. simulation (40 pC)

- BC2 R56=-24.7mm to get  $\sigma_z$ , and R56=-35 mm and L3 -90 deg to get  $\sigma_\delta$
- Shifted L2 phase to compare measurement with simulations (5% cut area)



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## X-band transverse deflector for both e-beam and x-ray pulse measurement\*:

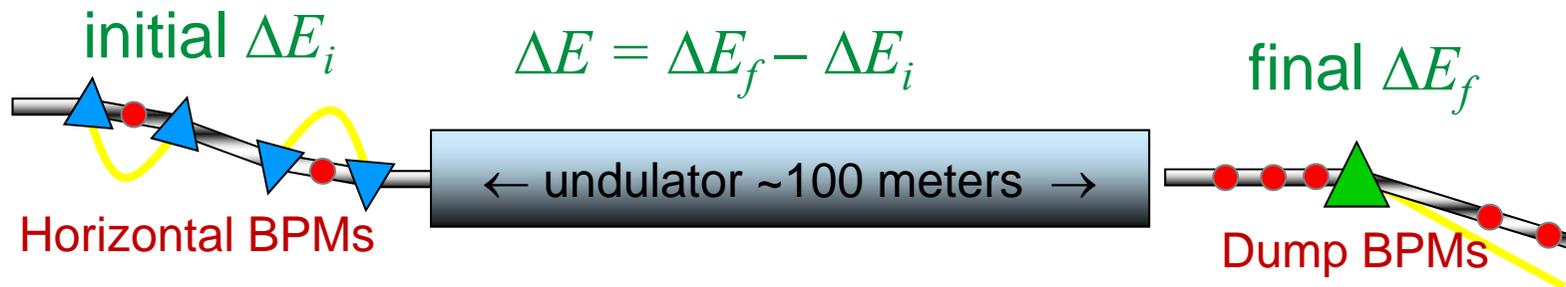
- Basic principle
- System layout and requirements
- Resolution
- simulation examples

\* *Y. Ding et al., SLAC-PUB-14534, submitted to PRSTAB.*

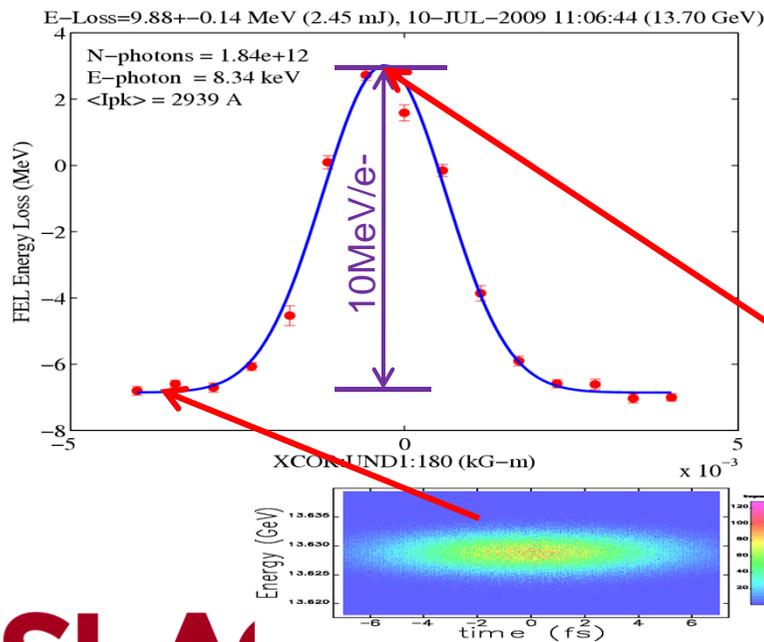
\* *Poster WEPB14, FEL11.*

# How to get the x-ray temporal profile

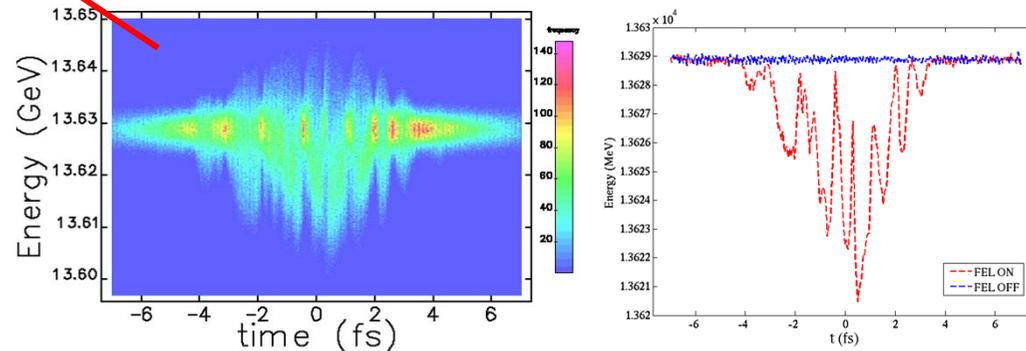
- The E-loss scan for measuring x-ray pulse energy:



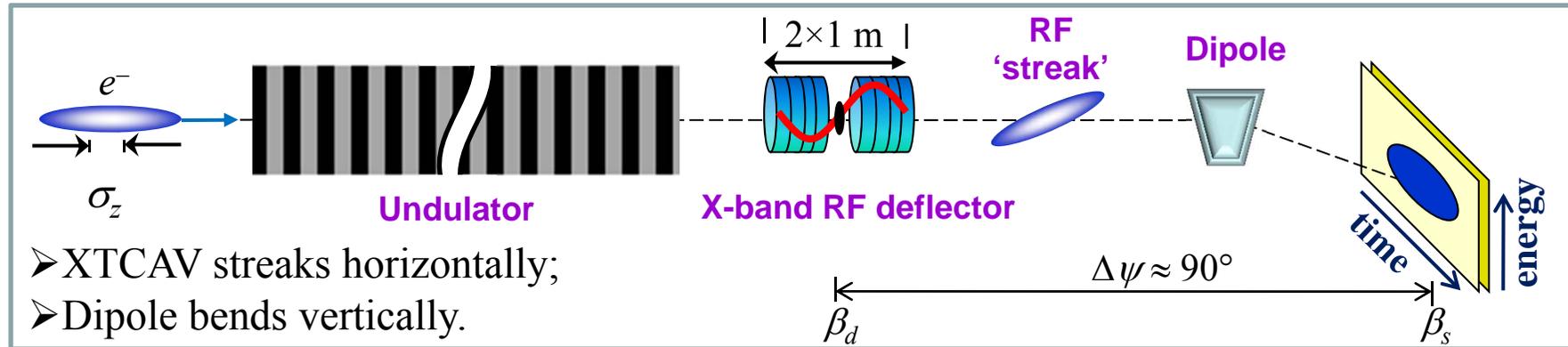
vary FEL power with oscillations & record  $e^-$  energy loss



We propose to streak the beam in time using a transverse deflector to measure the **time-resolved** energy loss, and energy spread, where the x-ray profile has been imprinted in the e-beam time-energy phase space.



# Layout and deflector parameters



## Deflector Parameters

Structure length	2 x 1 m
Frequency	11.424 GHz
Maximum kick	48 MV@40MW
Max rep. rate	120 Hz
Phase stability	<0.1 deg rms
Amplitude stability	<1%



(Juwen Wang)

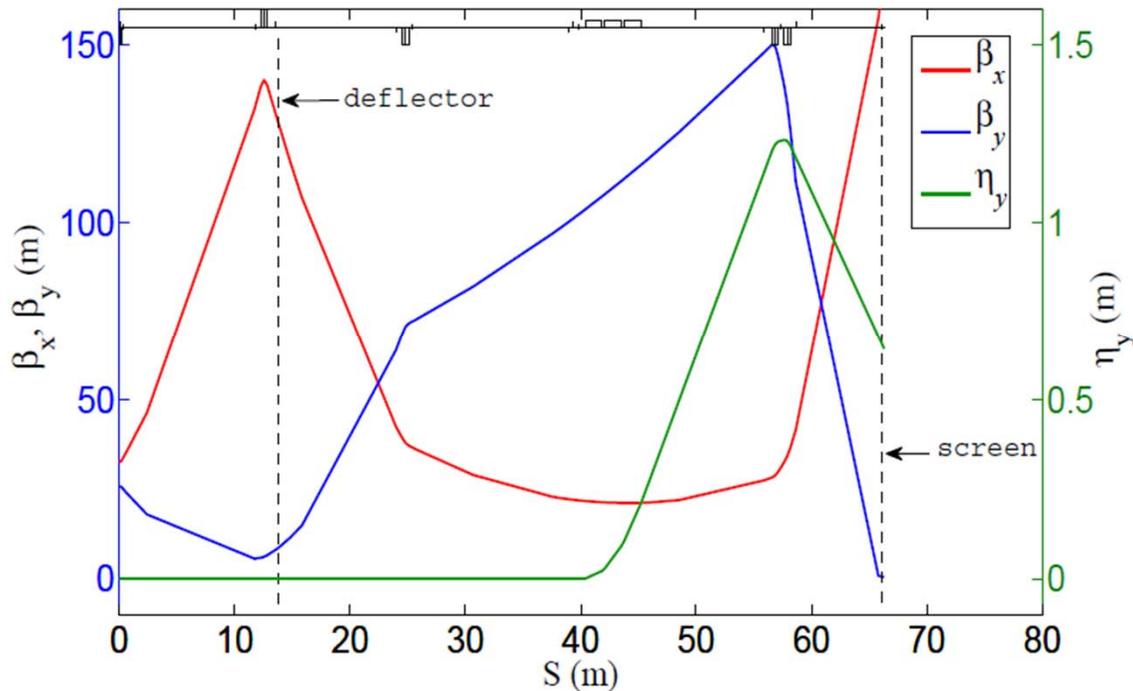
# Resolution and optics optimization

$$\text{Temporal resol.} = \frac{\sigma_{x0}}{cS} \propto \frac{\lambda_{rf}}{V_0} \sqrt{E \frac{\varepsilon_{N,x}}{\beta_{xd}}}$$

$$\text{Energy resol.} = \frac{\sigma_{y0}}{\eta_y} \propto \sqrt{\frac{\beta_{ys} \varepsilon_{N,y}}{E \eta_y}}$$

*S* is the calibration factor:

$$S = \frac{\sigma_x}{c\sigma_t} = \frac{eV_0}{pc} \sqrt{\beta_{xd}\beta_{xs}} |\sin\Delta\Psi| \frac{2\pi}{\lambda}$$



**HXR: (14GeV)**

$$\varepsilon_{N,x} = 0.6\mu\text{m}$$

$$S = 128,$$

$$\sigma_{t,R} \sim 2 \text{ fs};$$

$$\sigma_{\delta,R} = 7.3e-6$$

(100keV);

**SXR: (4.3GeV)**

$$\varepsilon_{N,x} = 0.6\mu\text{m}$$

$$S = 400,$$

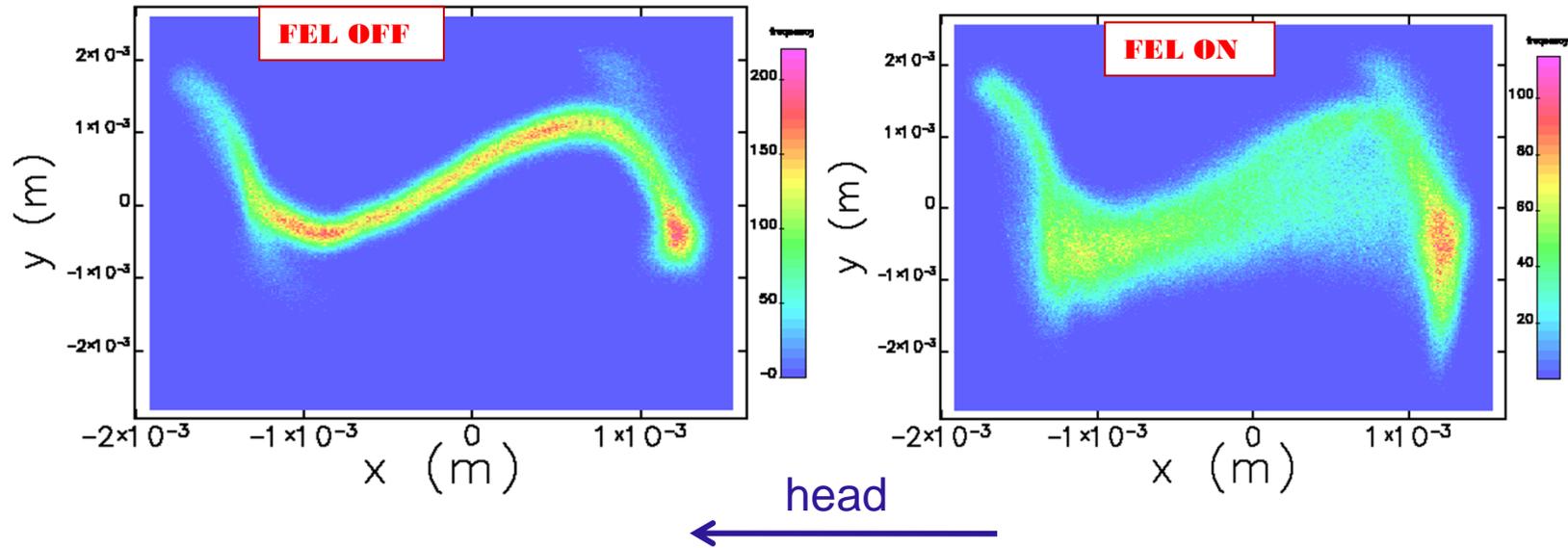
$$\sigma_{t,R} \sim 1 \text{ fs};$$

$$\sigma_{\delta,R} = 1.3e-5$$

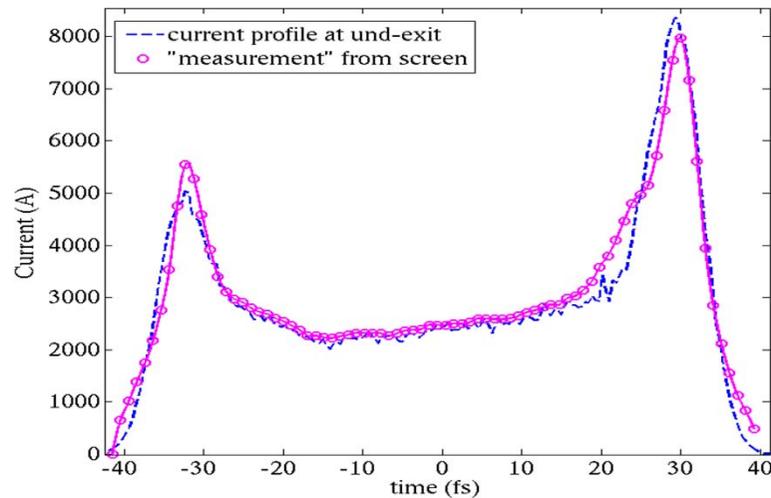
(56keV);

# Simulation example: hard x-ray S2E beam, 250pC

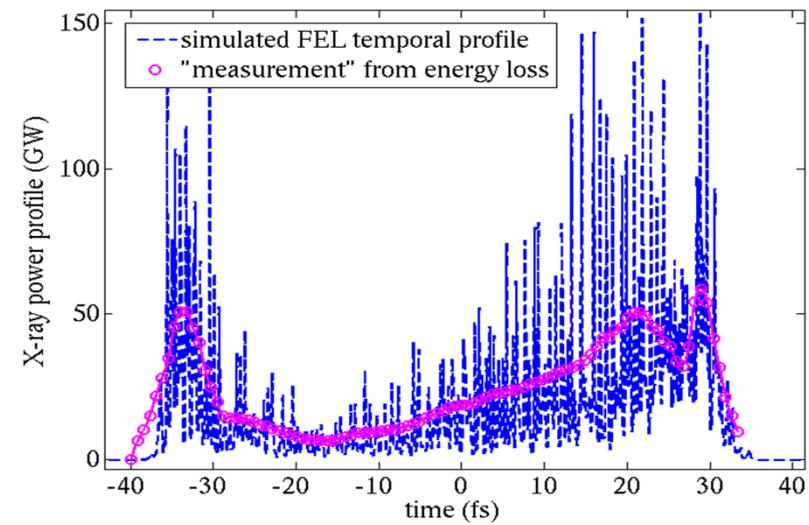
Screen



Reconstruction e-beam profile

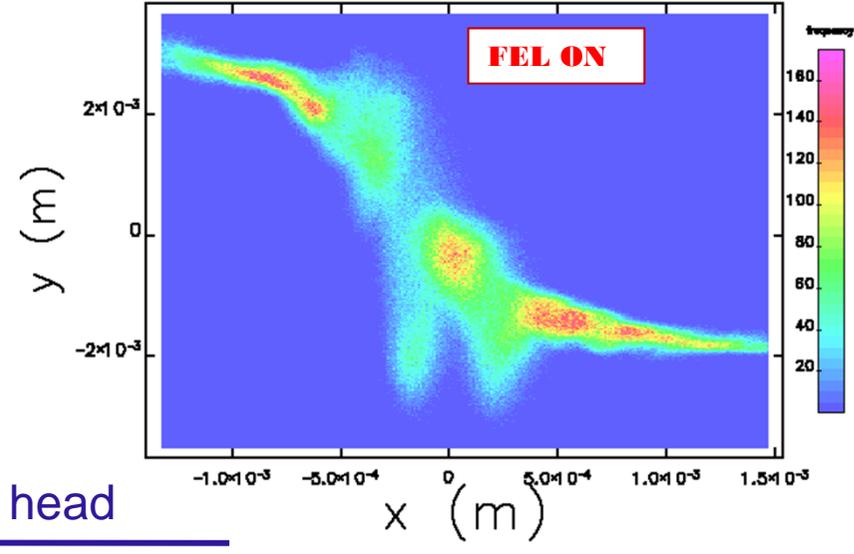
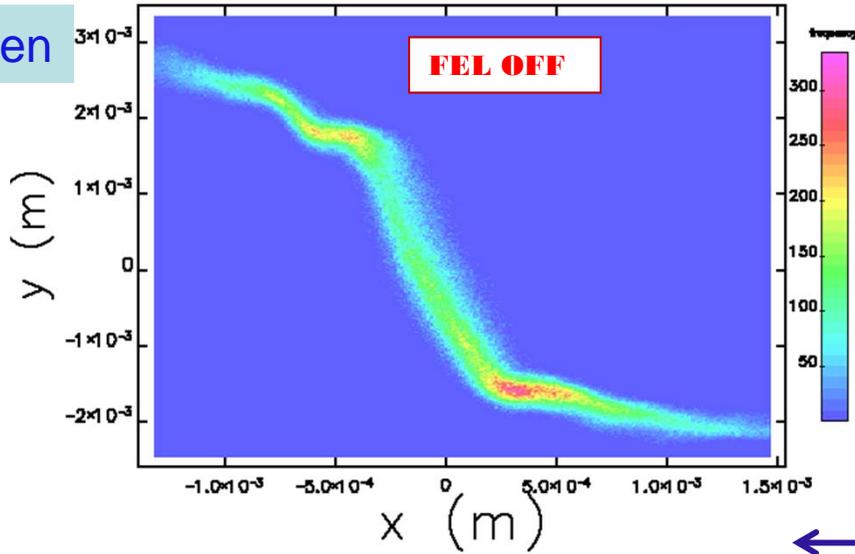


Reconstruction x-ray profile

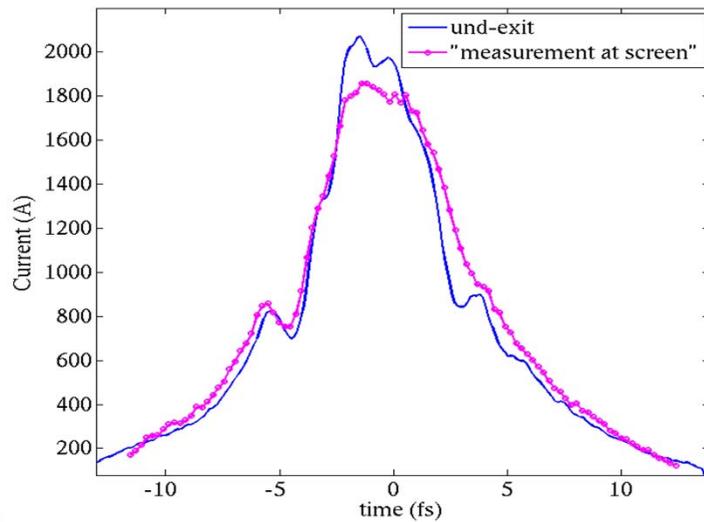


# Simulation example: soft x-ray S2E beam, 20pC

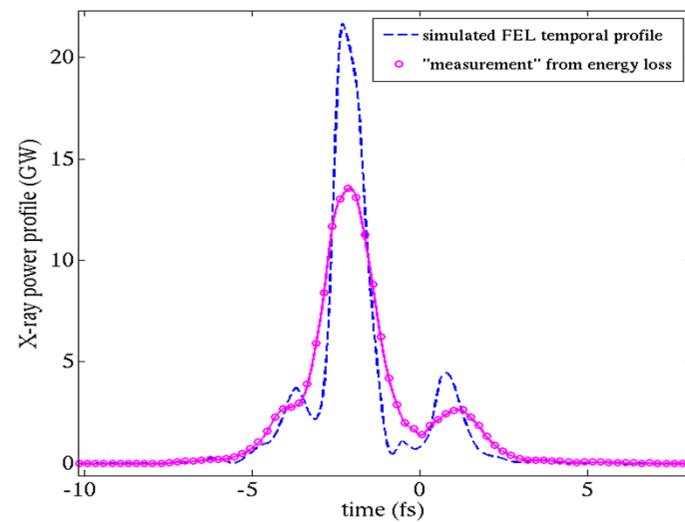
Screen



Reconstruction e-beam profile



Reconstruction x-ray profile



# Advantages of the X-band deflector method

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- ✓ High resolution, ~ few fs;
- ✓ Applicable for all radiation wavelength;
- ✓ Wide diagnostic range, few fs to few hundred fs;
- ✓ Profiles, single shot possible;
- ✓ No interruption with LCLS operation;
- ✓ **Both** e-beam and x-ray profiles.

*Generally applicable to other FEL facilities...*

# Jitter discussions ...

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- Calibration requires small arrival time and X-band deflector rf phase jitters:
  - use larger dump screen;
  - use phase cavity signal to correct;
- Electron energy jitter correction with BPMs:
  - energy correction with BPMs;
  - using energy spread is less sensitive than E-loss ;
- Current (bunch length) jitter correction:
  - cause difference on wake loss;
  - correction by correlation (same as E-loss scan).

# Streaking at optical frequencies?

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- Optical streaking with a Ti:Sa laser
  - use the slope of the intensity envelope to distinguish the different modulation periods.
  - calibrated with the laser wavelength. *Poster WEPB22.*
- Optical deflecting of the ionized low-energy electron beam with a circularly-polarized long-wavelength laser ( $\sim 10 \mu\text{m}$ )
  - No synchronization problem;
  - calibrated with the laser wavelength.

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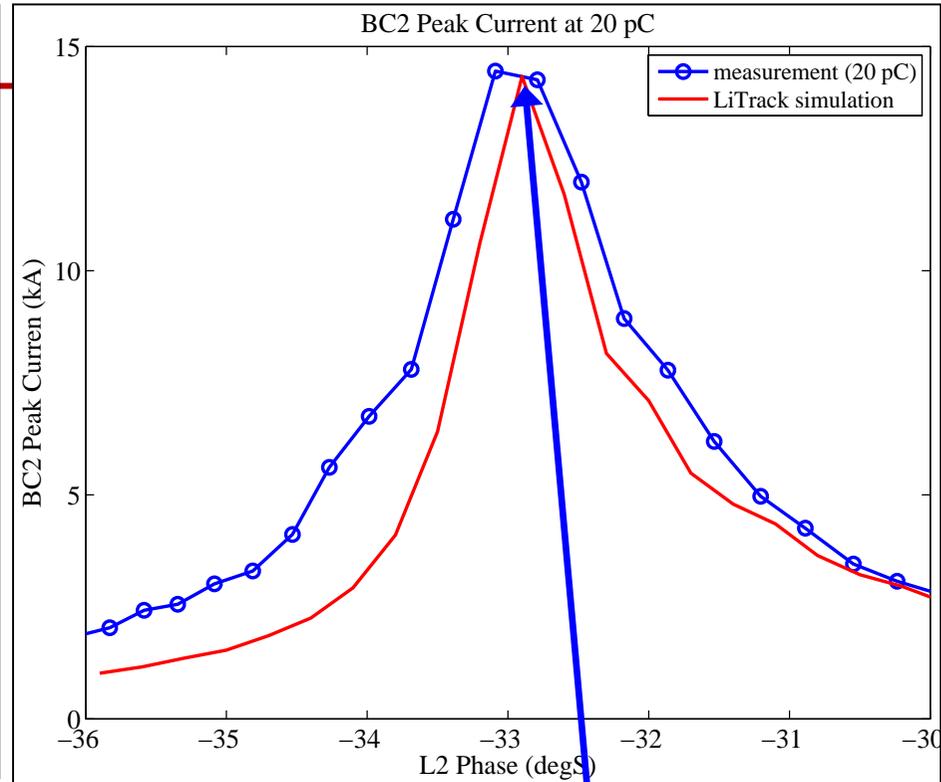
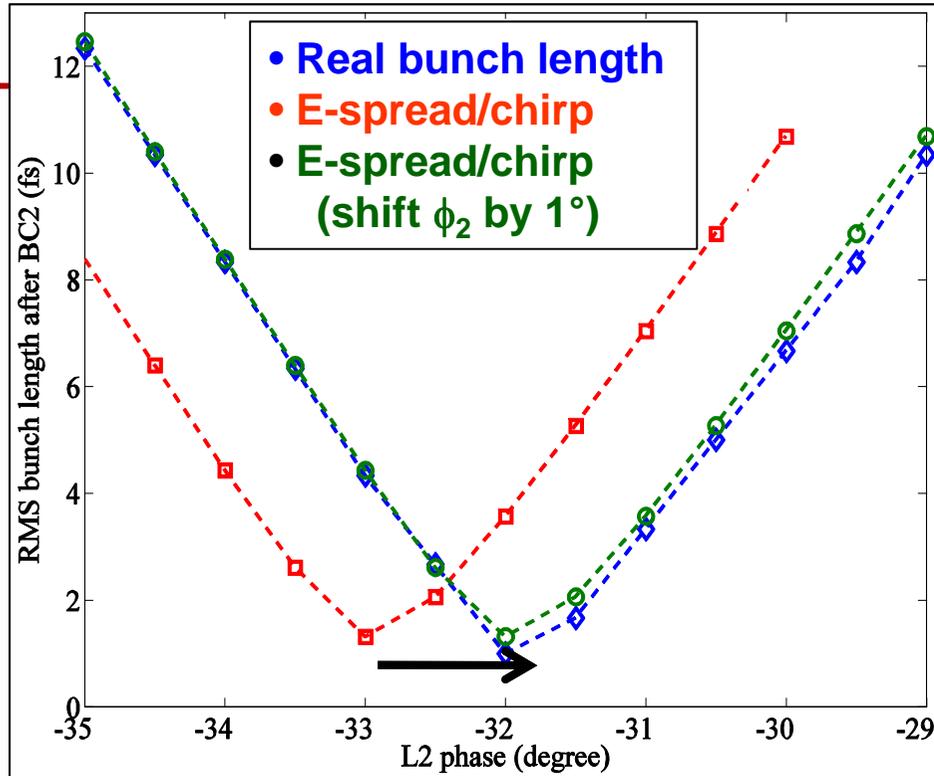
Thanks all my SLAC colleagues for helps and supports;

Thanks C. Behrens for X-band transverse deflector work;

Thanks the support from DOE Early-Career Award Program.

*We have postdoc position open at SLAC on this ultrashort diagnostic topic.*

# Wakefield compensation by shifting L2 phase



$R_{56}' = -7.18 \text{ mm}$

- Phase shift agrees with theory
- Wake effect can be corrected empirically by identifying full compression phase through CSR bunch length monitor

